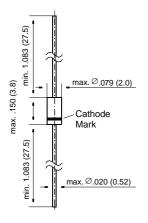
SD103A THRU SD103C

Schottky Diodes

<u>DO-35</u>



Dimensions in inches and (millimeters)

FEATURES

- For general purpose applications.
- The SD103 series is a metal-on-silicon Schottky barrier device which is protected by a PN junction guard ring. The low forward voltage drop and fast switching make it ideal for protection of MOS devices, steering, biasing, and coupling diodes for fast switching and low logic level applications. Other applications are click suppression, efficient full wave bridges in telephone subsets, and blocking diodes in rechargeable low voltage battery systems.
- This diode is also available in MiniMELF case with the type designation LL103A ... LL103C and SOD-123 case with the type designations SD103AW .. SD103CW.

MECHANICAL DATA

Case: DO-35 Glass Case Weight: approx. 0.13 g

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25 °C ambient temperature unless otherwise specified

RRM 40 RRM 30 RRM 20 Rot 40	0	V V V mW
ot 40	00 ¹⁾	m\//
		11100
SM 15	5	A
1:	25 ¹⁾	°C
s —	55 to +150 ¹⁾	°C
<u> </u>	s –	



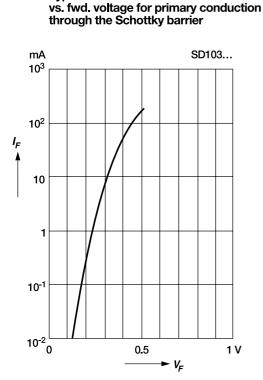
SD103A THRU SD103C

ELECTRICAL CHARACTERISTICS

Ratings at 25 °C ambient temperature unless otherwise specified

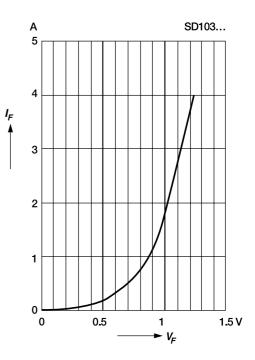
	Symbol	Min.	Тур.	Max.	Unit
Leakage CurrentSD103Aat $V_R = 30 V$ SD103Bat $V_R = 20 V$ SD103Bat $V_R = 10 V$ SD103C	l _R I _R I _R			5 5 5	μΑ μΑ μΑ
Forward Voltage Drop at I _F = 20 mA at I _F = 200 mA	V _F V _F			0.37 0.6	V V
Junction Capacitance at $V_R = 0 V$, f = 1 MHz	C _{tot}	-	50	-	pF
Reverse Recovery Time at $I_F = I_R = 50$ mA to 200 mA, recover to 0.1 I_R	t _{rr}	_	10	-	ns
Thermal Resistance Junction to Ambient Air	R _{thJA}	-	-	0.31)	K/mW
¹⁾ Valid provided that leads at a distance of 4 mm	from case are	kept at ambi	ent temperati	ure (DO-35)	1

RATINGS AND CHARACTERISTIC CURVES SD103A THRU SD103C



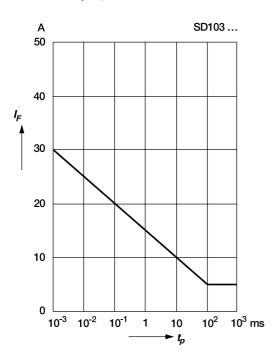
Typical variation of fwd. current

Typical high current forward conduction curve $t_p = 300$ ms, duty cycle = 2%



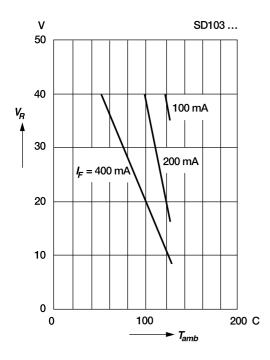


RATINGS AND CHARACTERISTIC CURVES SD103A THRU SD103C

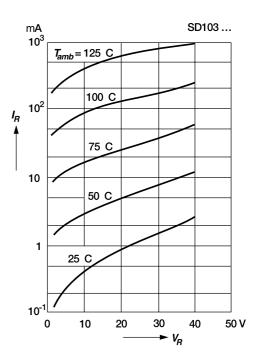


Typical non repetitive forward surge current versus pulse width Rectangular pulse

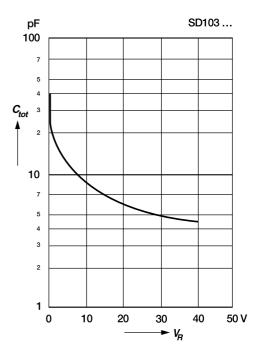
Blocking voltage deration versus temperature at various average forward currents



Typical variation of reverse current at various temperatures



Typical capacitance versus reverse voltage



GENERAL SEMICONDUCTOR[®]